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EP 0 907 076 A3

(12)

EUROPEAN PATENT APPLICATION

(88) Date of publication A3: 04.10.2000 Bulletin 2000/40

(51) Int. Cl.⁷: **H01J 37/063**, ·G01B 7/34, G01N 27/00, H02N 1/00

(11)

- (43) Date of publication A2:07.04.1999 Bulletin 1999/14
- (21) Application number: 98116809.9
- (22) Date of filing: 12.05.1992
- (84) Designated Contracting States:
 AT BE CH DE DK ES FR GB GR IT LI LU MC NL
 SE
- (30) Priority: 14.05.1991 US 699390 14.04.1992 US 868138
- (62) Document number(s) of the earlier application(s) in accordance with Art. 76 EPC: 92912228.1 / 0 584 233
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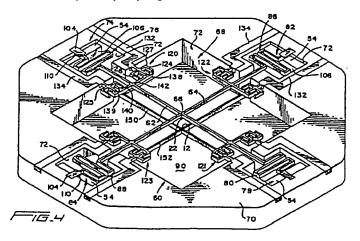
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(54) Methods of fabricating integrated, aligned tunneling tip pairs

(57) Self-aligned, opposed, nanometer dimension tips (12, 22) are fabricated in pairs, one of each pair being located on a movable (24) single crystal beam, with the beam being movable in three dimensions with respect to a substrate (18) carrying the other tip (12) of a pair. Motion of one tip with respect to the other is controlled or sensed by transducers (120, 122, 124, 126) formed on the supporting beams (62, 64). Spring

means (76, 80, 86, 88) in each beam allow axial motion of the beam. The tips (12, 22) and beams (62, 64) are fabricated from single crystal silicon substrate (18) and the tips (12, 22) may be electrically isolated from the substrate (18) by fabricating insulating segments (40, 54) in the beam structure.





EUROPEAN SEARCH REPORT

Application Number

EP 98 11 6809

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	Place of search	Date of completion of the search	<u> </u>	Examiner	
	THE HAGUE	15 August 2000	Cle	vorn, J	
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EUROPEAN SEARCH REPORT

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ANNEX TO THE EUROPEAN SEARCH REPORT ON EUROPEAN PATENT APPLICATION NO.

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